

Search Notes

Application/Control No.

09/677,401

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under
Reexamination

KERN ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	14	update 4/06	Jn
17		1	
34			
38			
39			
463	25		
235	380		
381		✓	✓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner